

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10628224	LEE ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	NHAN T TRAN	2622

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
348	373-376	6/24/2007	NT
348	333.06	6/24/2007	NT

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	6/24/2007	NT
348/14.01-14.16 (text search - see search history)	9/27/2007	NT
348/333.01-333.12 (text search - see search history)	9/27/2007	NT
text search all class 379	9/27/2007	NT
455/550.1, 556.1, 566 (text search - see search history)	9/28/2007	NT
Text seach all classes in the databases listed above	9/28/2007	NT
Inventorship search	9/28/2007	NT
Updated EAST search	4/4/2008	NT
348/211.2 (text search - see search history)	4/4/2008	NT

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
ALL	PGPUB text search - see search history	4/4/2008	NT